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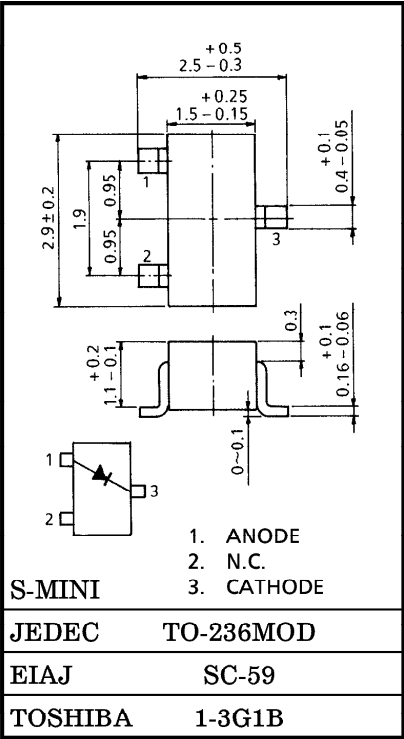
ULTRA HIGH SPEED SWITCHING APPLICATION.

Unit in mm

- Low Forward Voltage :  $V_F(3)=0.50V$  (Typ.)
- Fast Reverse Recovery Time :  $t_{rr}=20ns$  (Typ.)
- High Average Forward Current :  $I_O=0.5A$  (Max.)

MAXIMUM RATINGS (Ta = 25°C)

| CHARACTERISTIC                 | SYMBOL    | RATING  | UNIT |
|--------------------------------|-----------|---------|------|
| Maximum (Peak) Reverse Voltage | $V_{RM}$  | 25      | V    |
| Reverse Voltage                | $V_R$     | 20      | V    |
| Maximum (Peak) Forward Current | $I_{FM}$  | 1500    | mA   |
| Average Forward Current        | $I_O$     | 500     | mA   |
| Surge Current (10ms)           | $I_{FSM}$ | 5       | A    |
| Power Dissipation              | P         | 200     | mW   |
| Junction Temperature           | $T_j$     | 125     | °C   |
| Storage Temperature            | $T_{stg}$ | -55~125 | °C   |
| Operating Temperature          | $T_{opr}$ | -40~100 | °C   |



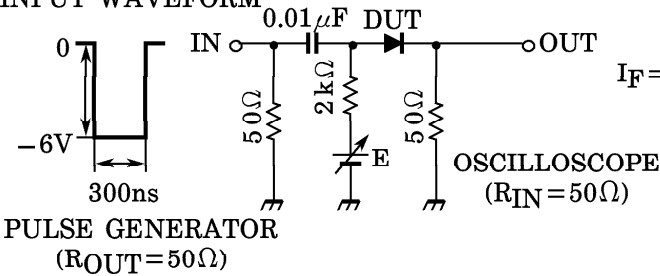
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

Weight : 0.012g

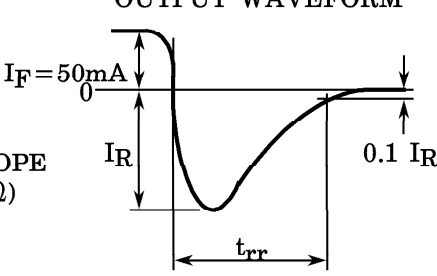
| CHARACTERISTIC        | SYMBOL   | TEST CONDITION     | MIN. | TYP. | MAX. | UNIT    |
|-----------------------|----------|--------------------|------|------|------|---------|
| Forward Voltage       | $V_F(1)$ | $I_F=10mA$         | —    | 0.30 | —    | V       |
|                       | $V_F(2)$ | $I_F=100mA$        | —    | 0.38 | —    |         |
|                       | $V_F(3)$ | $I_F=500mA$        | —    | 0.50 | 0.55 |         |
| Reverse Current       | $I_R(1)$ | $V_R=10V$          | —    | —    | 20   | $\mu A$ |
|                       | $I_R(2)$ | $V_R=20V$          | —    | —    | 100  |         |
| Total Capacitance     | $C_T$    | $V_R=0, f=1MHz$    | —    | 120  | —    | pF      |
| Reverse Recovery Time | $t_{rr}$ | $I_F=50mA$ (Fig.1) | —    | 20   | —    | ns      |

Fig.1 Reverse Recovery time ( $t_{rr}$ ) test circuit

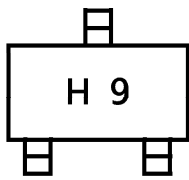
INPUT WAVEFORM



OUTPUT WAVEFORM

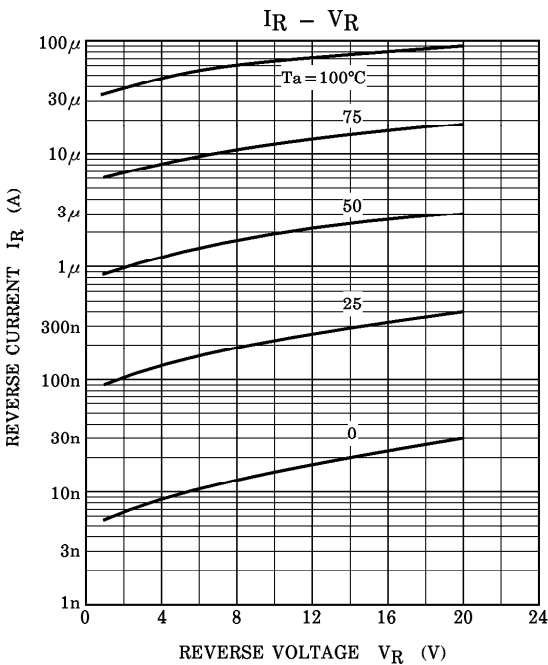
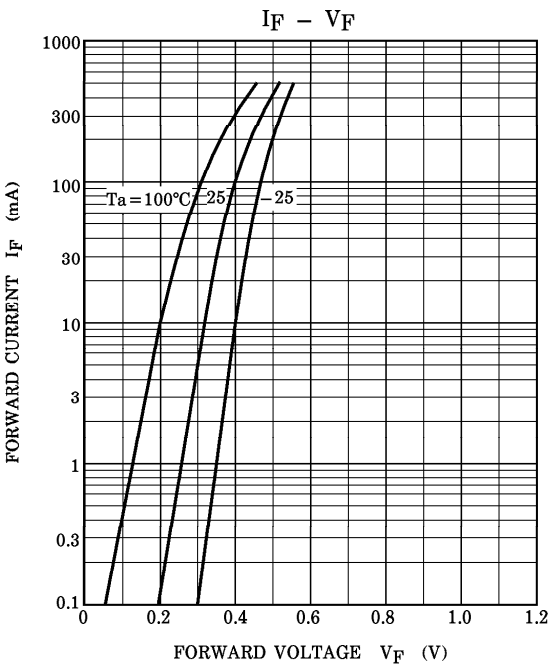


MARKING



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